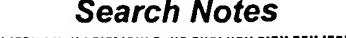


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/806,140	CHIU, JANICE
	Examiner	Art Unit
	Pablo N. Tran	2618

SEARCHED			
Class	Subclass	Date	Examiner
455	226.4	06/21/06	PL
	226.1-226.2		
115.1			
115.3 - 115.4			
127.2 - 127.3			
232.1			
500			
513			
62.1			
67.7			
67.11			
91			
157-138			
134			

Search Notes (continued)



Application/Control No.

10/806,140

Examiner

Pablo N. Tran

**Applicant(s)/Patent under
Reexamination**

CHIU, JANICE

Art Unit

2618

SEARCHED			
Class	Subclass	Date	Examiner
	308 311		
955	144	18/2/60	RJ
	19A.2		
	241.1		
	245.i		
	252		
	281.1		
	293.2		
	2T7.2		
	341		
330	140		
	279		
327	560		
328	317-318		
330	133-134		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner